

Notice of References Cited	Application/Control No. 10/593,630		Applicant(s)/Patent Under Reexamination IDE ET AL.	
	Examiner JOSE M. DIAZ		Art Unit 2879	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0104672 A1	06-2004	Shiang et al.	313/506
*	B	US-2005/0051791 A1	03-2005	Gotoh et al.	257/099
*	C	US-2005/0233156 A1	10-2005	Senzaki et al.	428/446
*	D	US-2006/0097630 A1	05-2006	Shiokawa et al.	313/504
*	E	US-2007/0099024 A1	05-2007	Nii et al.	428/690
*	F	US-2009/0153030 A1	06-2009	Huo et al.	313/504
*	G	US-2011/0284893 A1	11-2011	Hoeppe et al.	257/98
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 2004095892 A1	11-2004	World Intellect	KUMA, HITOSHI	H05B 33/26
	O	WO 2005029923 A1	03-2005	World Intellect	Nii et al.	H05B 33/14
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.